

Development and applications of fast-timing semiconductor devices for
US-Japan collaboration

Contribution ID: 5

Type: **not specified**

SOI CMOS development in Japan

Friday 22 February 2019 10:00 (1 hour)

Presenters: HARA, Kazuhiko (University of Tsukuba (JP)); Dr YAMADA, Miho (KEK); HITOSHI, Murayama (Tsukuba); IWANAMI, Shikie (Tsukuba); Mr ONO, Shun (KEK)

Session Classification: Other Experiment for FTBF testbeam